

# La spectroscopie d'absorption de rayons X dans l'analyse de verres dopés aux terres rares

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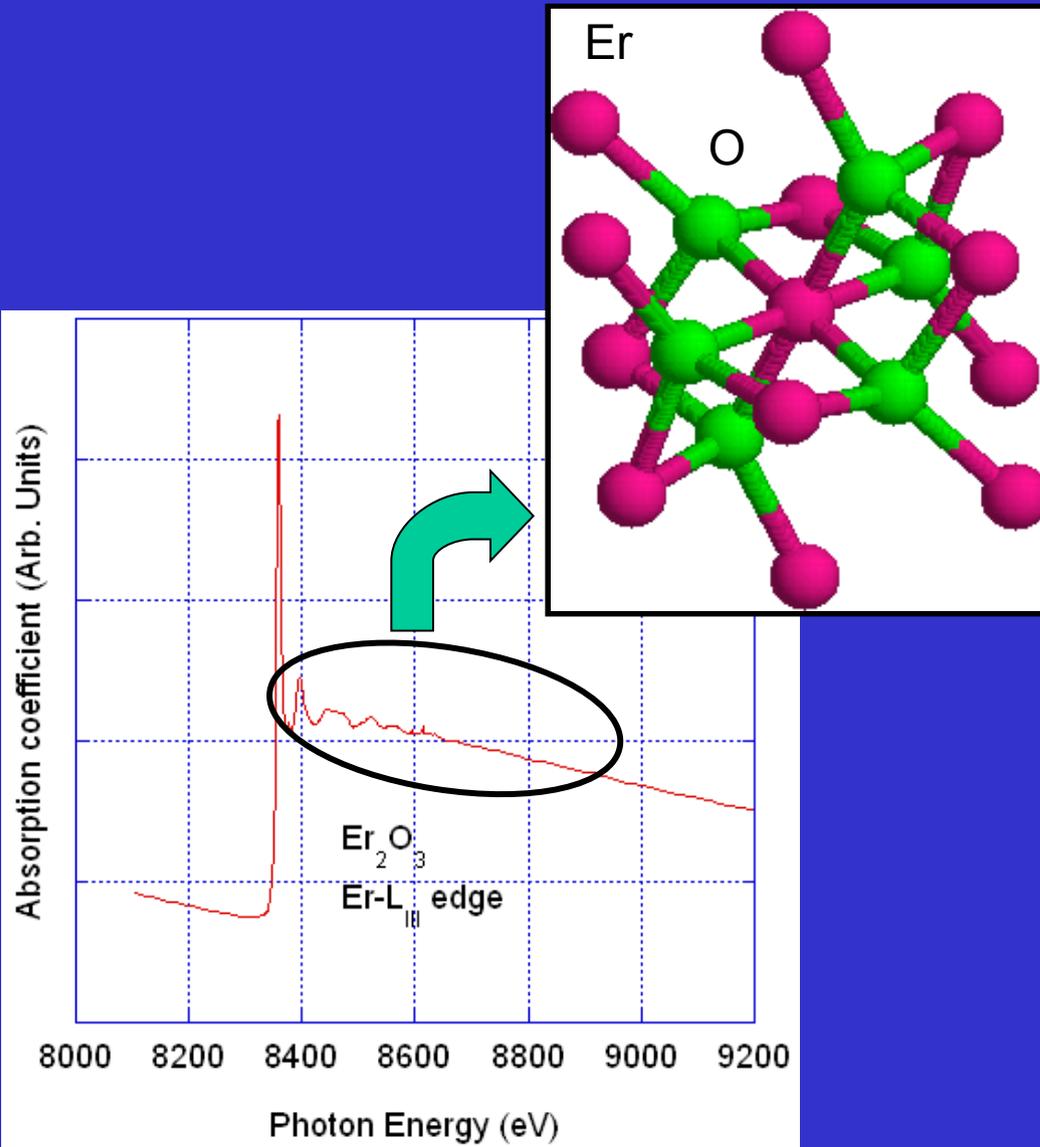


# Layout

- Introduction to XAS
- Description of GILDA
- Experimental examples

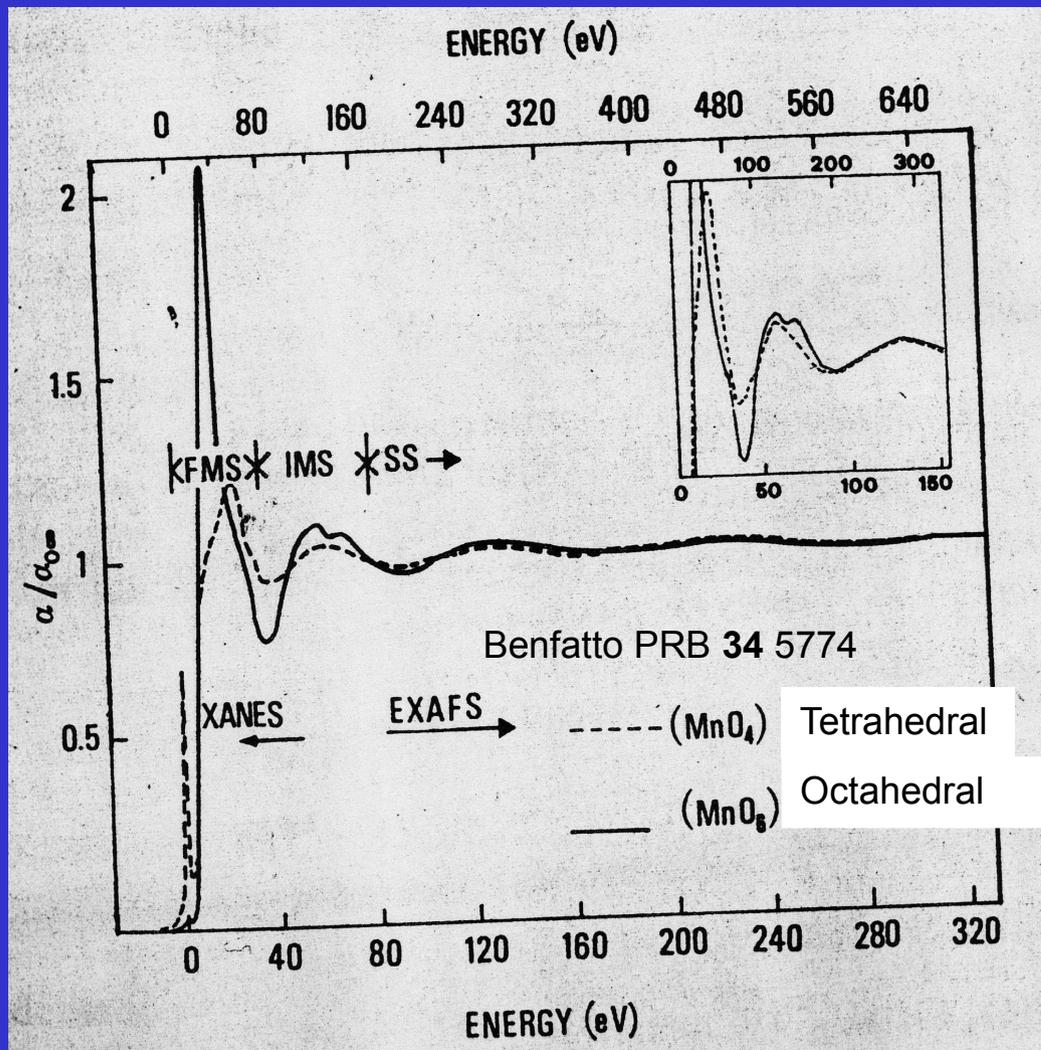
# Introduction to the XAS technique

# X-ray Absorption Spectroscopy-XAS



- The information is retrieved from the oscillations above the absorption edge
- Local structural parameters
  - N (number of neighbors),
  - R (distance),
  - $\sigma^2$  Debye-Waller factor (disorder)
- No need for long range order
- Typical accuracy 1% R, 10% N, 20%  $\sigma^2$

# XAS spectrum regions



2 regions can be defined in the absorption spectrum

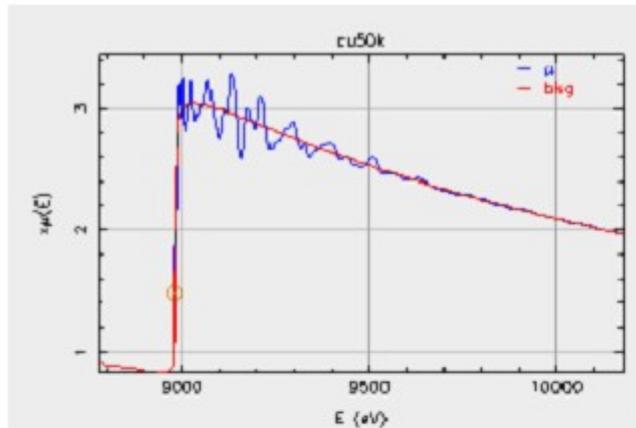
## • XANES

- Up to 50 eV
- Long photoelectron wavelength
- Electronic structure
- Local geometry, symmetry
- Complex scattering processes

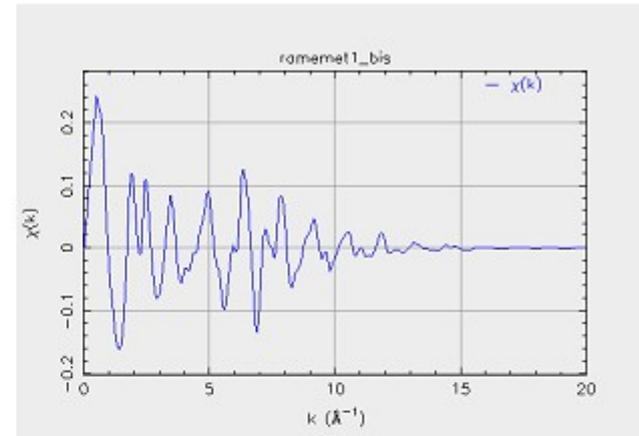
## • EXAFS

- Short photoelectron wavelength
- Quantitative
- Dominated by single scattering

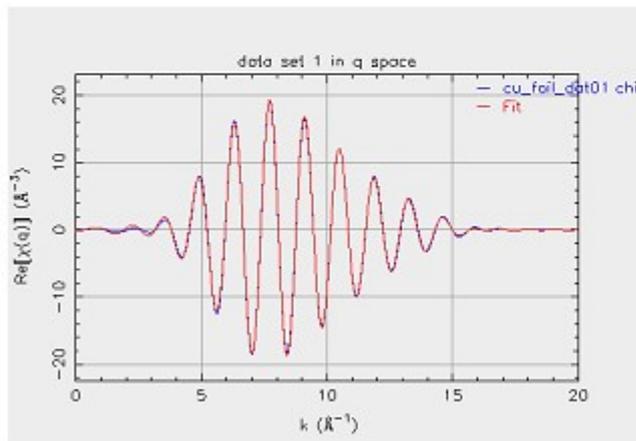
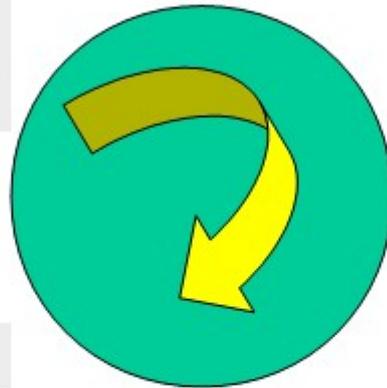
# EXAFS data analysis



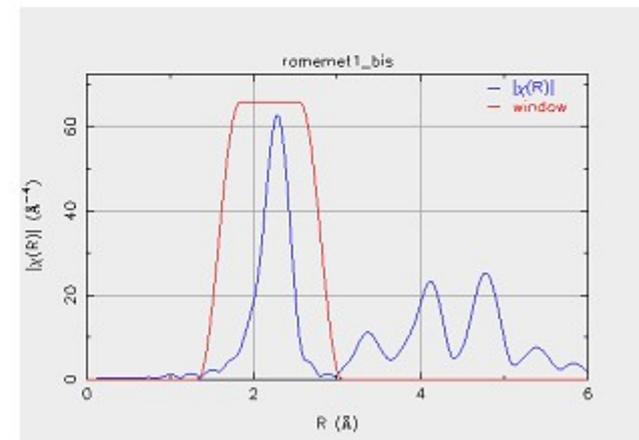
Background subtraction



Oscillatory  $\chi$  function



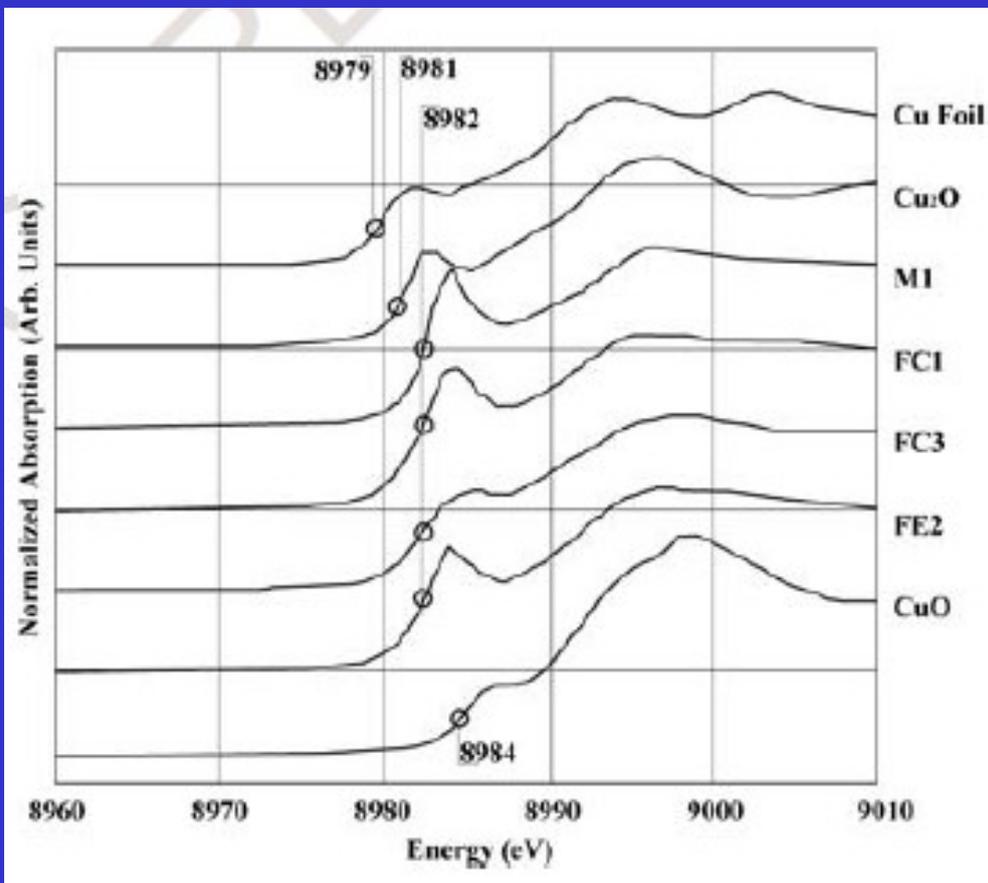
Back-transform and  
Multiparameter fit



Fourier Transform

# XANES

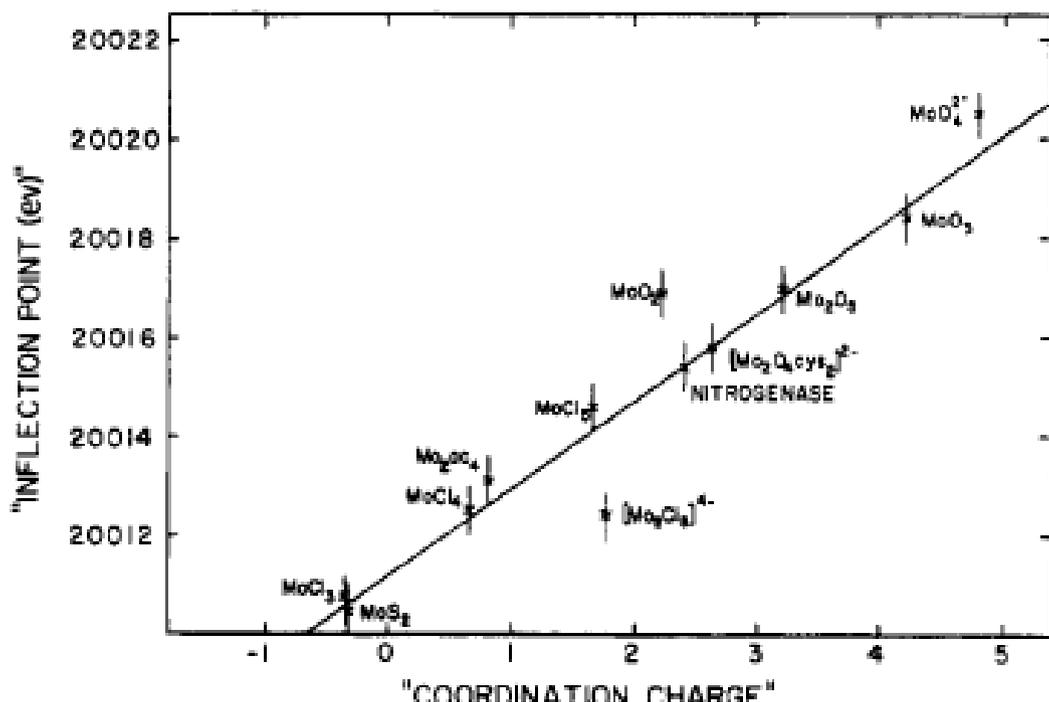
Some fundamental data can be extracted from the near edge region



I: Valence state  
The position of the edge  
(1<sup>st</sup> inflection point)  
depends on the charge  
on the ion.

# Qualitative XANES data analysis

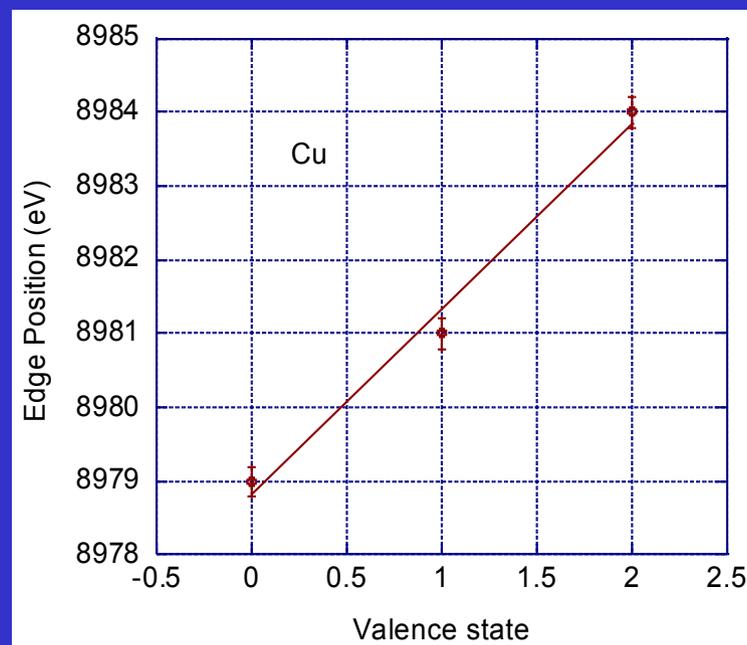
The valence state of a chemical specie can be derived from the position of the first inflection point of  $\mu(E)$ .



S. P. Cramer, T. K. Eccles, F. W. Kutzler, Keith O. Hodgson

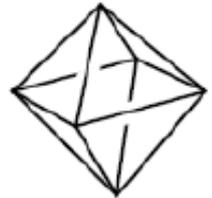
L. E. Mortenson

*Journal of the American Chemical Society* / 98:5 / March 3, 1976

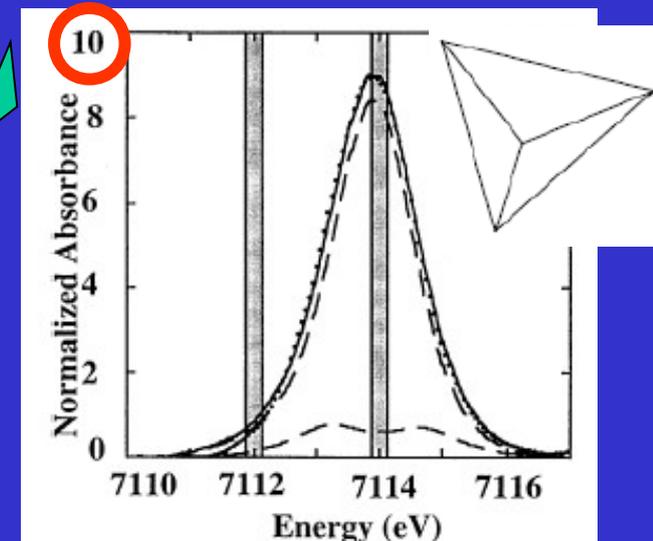
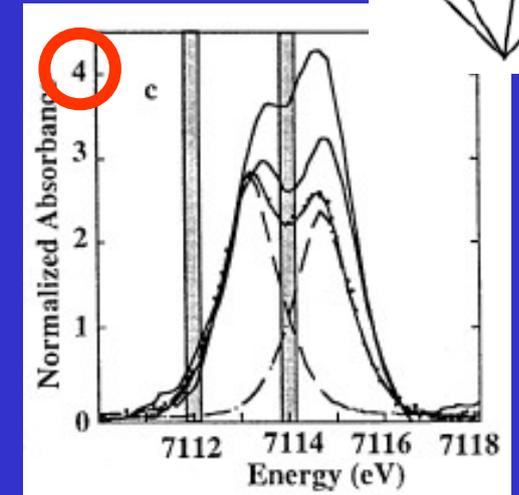
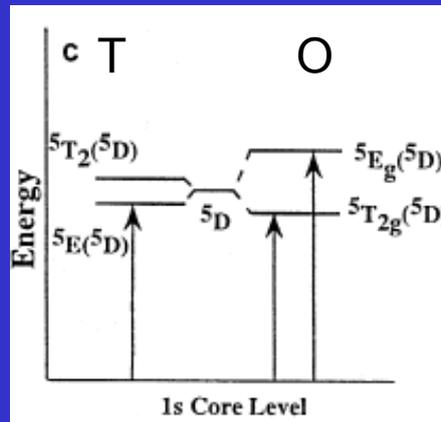
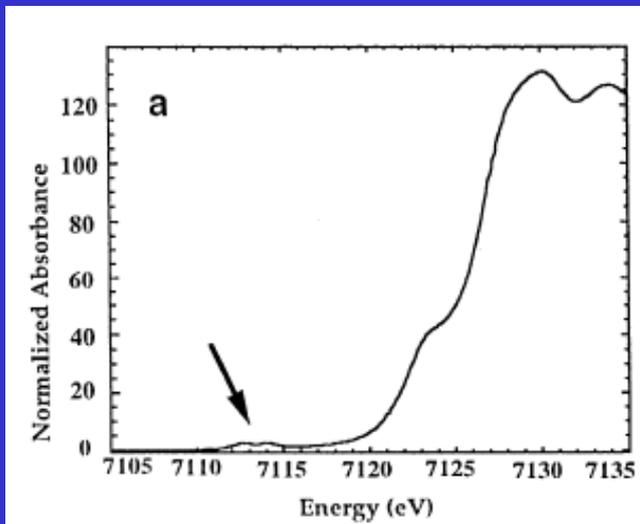


# Qualitative XANES data analysis

L. Galois<sup>\*</sup>, G. Calas, M.A. Arrio *Chemical Geology* 174 (2001) 307–319

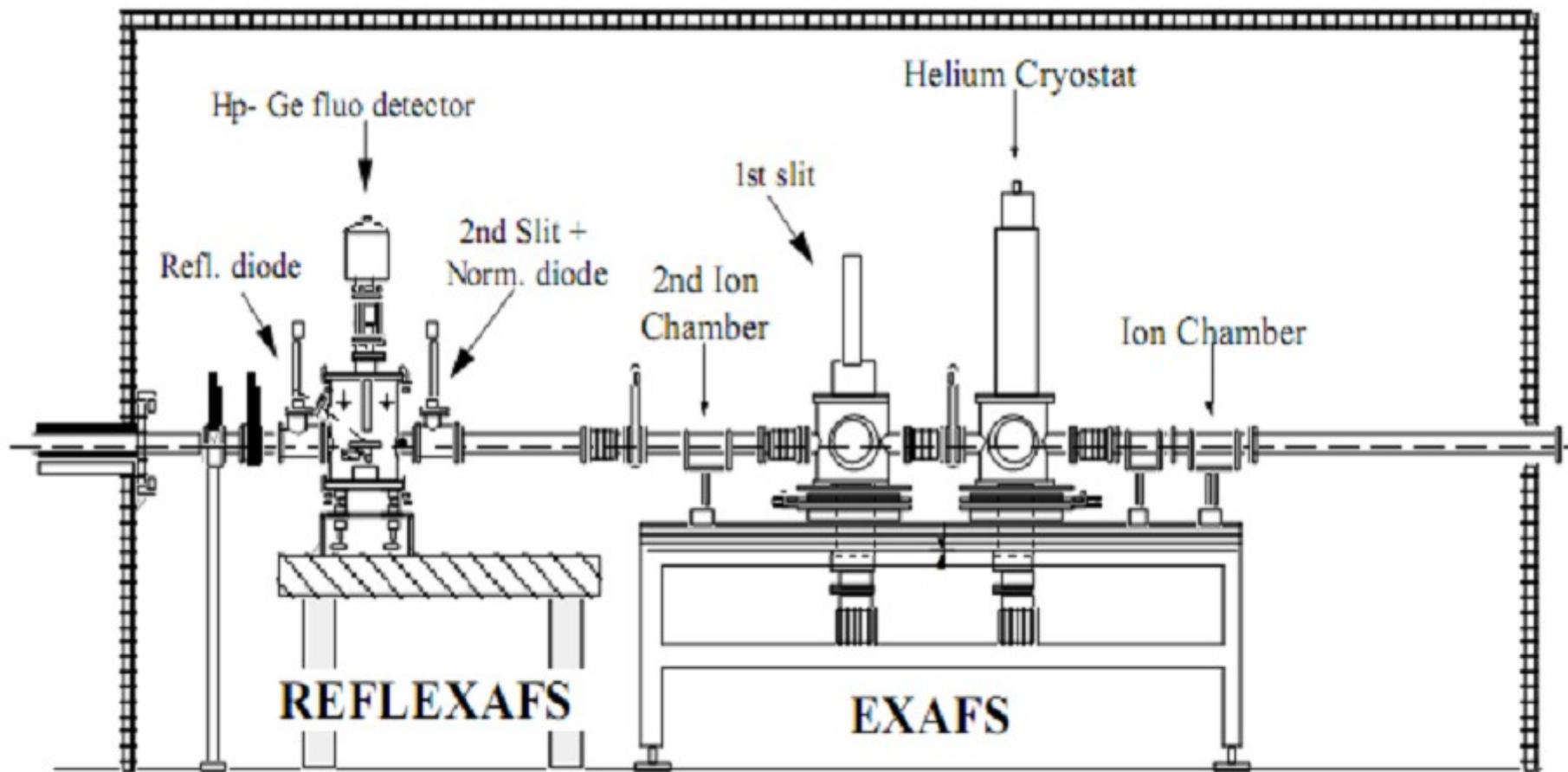


- Octahedral vs Tetrahedral site

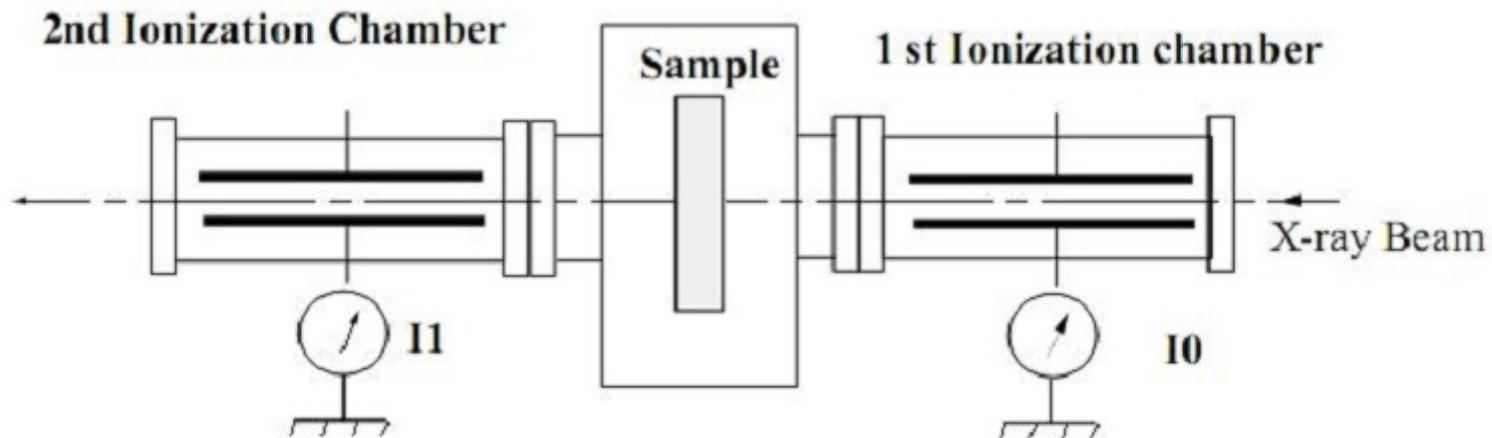


Analysis of the small features before the edge (1s-3d in Fe<sup>3+</sup> comp.)

# Apparatus for measuring XAS



# Measuring $\mu$ : direct method

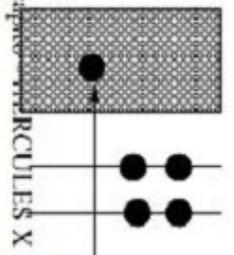


$$I_1 = I_0 * \exp (-\mu x)$$

$$\mu = -\ln (I_1/I_0)$$

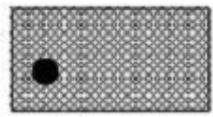
# Indirect methods

6. F. D. A. C. P. M. R. C. U. L. E. S. X

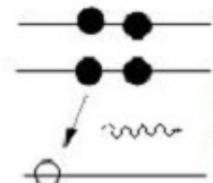


Ionized state

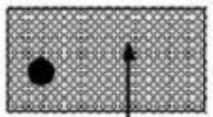
○ = Hole  
● = electron



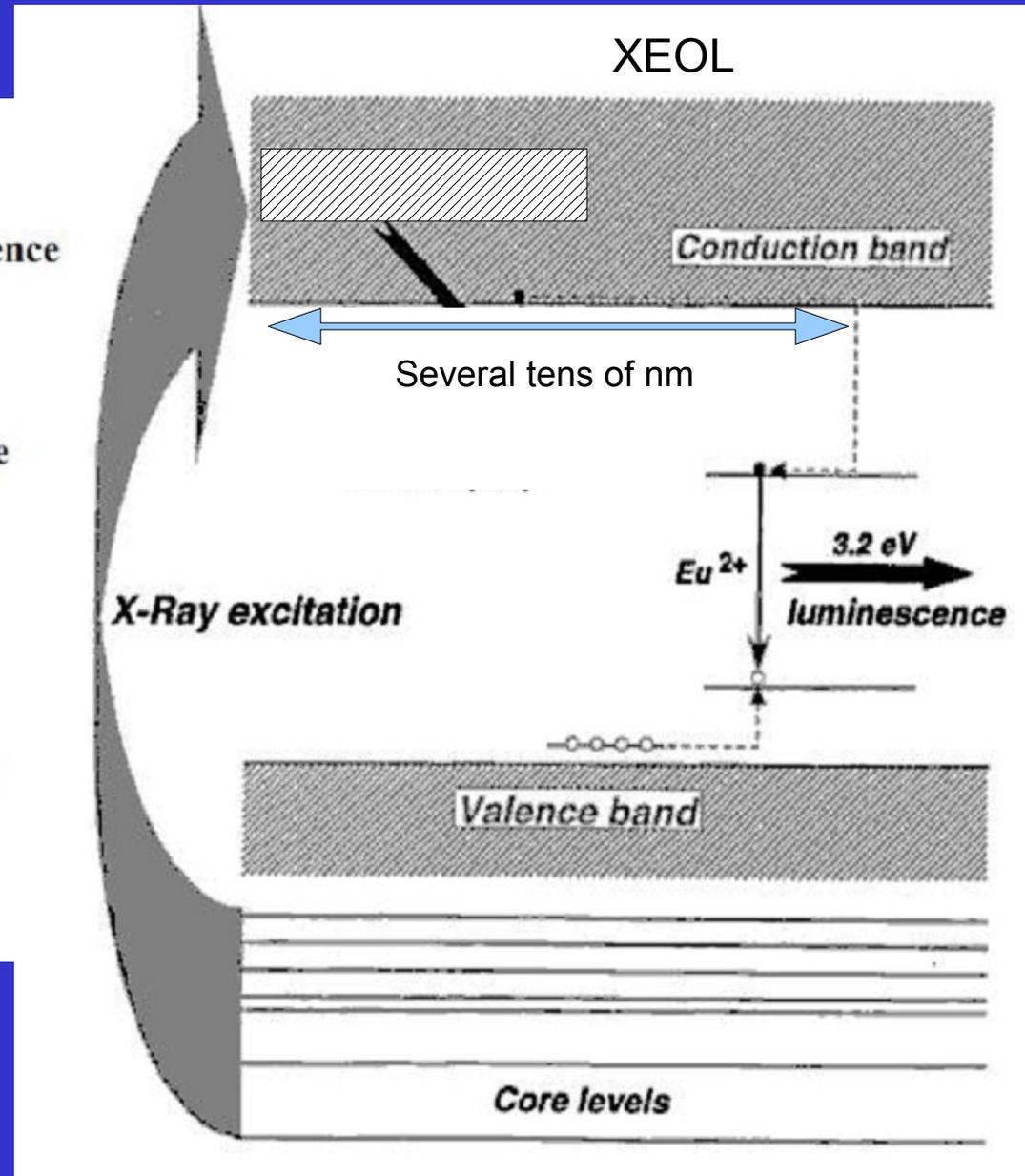
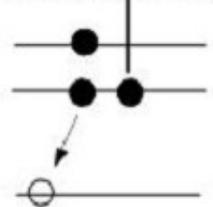
Fluorescence



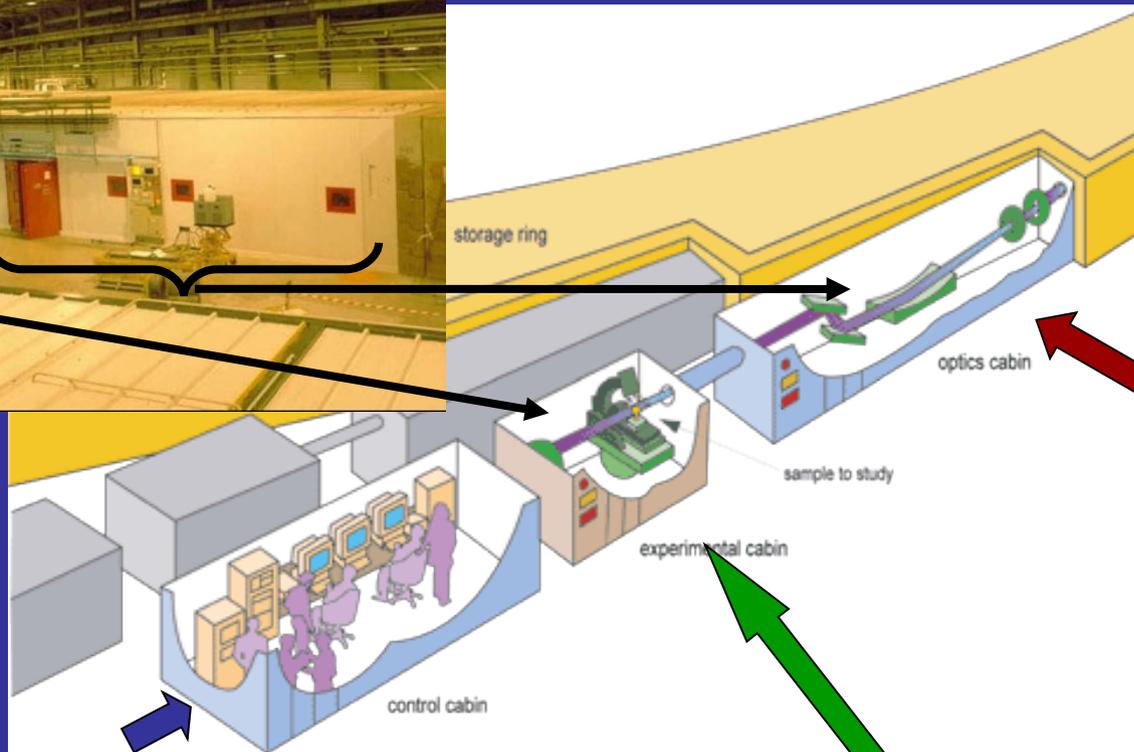
X-ray fluorescence



Auger electron Yield



# The GILDA Beamline



## Optic Hutch

- beam sizing
- mono-chromatization
- focalization

## Control room

- Remote instrumentation control
- Data analysis

## 3 Experimental cabins

- XAS Hutch (Instrumentation for XAS experiments)
- Diffraction Hutch (Instrumentation for XRD experiments)
- “Open Hutch” (Open to user’s experimental apparatus)

# Some figures

- Energy range: 5-90 keV
- Crystals Si(111), (311), (511), (755)
- Beam size 2\*1 mm<sup>2</sup> >> 0.2\*0.2 mm<sup>2</sup>
- Beam intensity 10<sup>11</sup>-10<sup>9</sup> ph/s
- HP-Ge detectors for X-ray fluorescence

Periodic Table of the Elements © www.elementsdatabase.com

Edges:  
 K —  
 L —

1 H																	2 He																												
3 Li	4 Be											5 B	6 C	7 N	8 O	9 F	10 Ne																												
11 Na	12 Mg											13 Al	14 Si	15 P	16 S	17 Cl	18 Ar																												
19 K	20 Ca	21 Sc	22 Ti	23 V	24 Cr	25 Mn	26 Fe	27 Co	28 Ni	29 Cu	30 Zn	31 Ga	32 Ge	33 As	34 Se	35 Br	36 Kr																												
37 Rb	38 Sr	39 Y	40 Zr	41 Nb	42 Mo	43 Tc	44 Ru	45 Rh	46 Pd	47 Ag	48 Cd	49 In	50 Sn	51 Sb	52 Te	53 I	54 Xe																												
55 Cs	56 Ba	57 La	72 Hf	73 Ta	74 W	75 Re	76 Os	77 Ir	78 Pt	79 Au	80 Hg	81 Tl	82 Pb	83 Bi	84 Po	85 At	86 Rn																												
87 Fr	88 Ra	89 Ac	104 Unq	105 Unp	106 Unh	107 Uns	108 Uno	109 Une	110 Uun																																				
<table border="1" style="width: 100%; border-collapse: collapse; text-align: center;"> <tr> <td>58 Ce</td> <td>59 Pr</td> <td>60 Nd</td> <td>61 Pm</td> <td>62 Sm</td> <td>63 Eu</td> <td>64 Gd</td> <td>65 Tb</td> <td>66 Dy</td> <td>67 Ho</td> <td>68 Er</td> <td>69 Tm</td> <td>70 Yb</td> <td>71 Lu</td> </tr> <tr> <td>90 Th</td> <td>91 Pa</td> <td>92 U</td> <td>93 Np</td> <td>94 Pu</td> <td>95 Am</td> <td>96 Cm</td> <td>97 Bk</td> <td>98 Cf</td> <td>99 Es</td> <td>100 Fm</td> <td>101 Md</td> <td>102 No</td> <td>103 Lr</td> </tr> </table>																		58 Ce	59 Pr	60 Nd	61 Pm	62 Sm	63 Eu	64 Gd	65 Tb	66 Dy	67 Ho	68 Er	69 Tm	70 Yb	71 Lu	90 Th	91 Pa	92 U	93 Np	94 Pu	95 Am	96 Cm	97 Bk	98 Cf	99 Es	100 Fm	101 Md	102 No	103 Lr
58 Ce	59 Pr	60 Nd	61 Pm	62 Sm	63 Eu	64 Gd	65 Tb	66 Dy	67 Ho	68 Er	69 Tm	70 Yb	71 Lu																																
90 Th	91 Pa	92 U	93 Np	94 Pu	95 Am	96 Cm	97 Bk	98 Cf	99 Es	100 Fm	101 Md	102 No	103 Lr																																

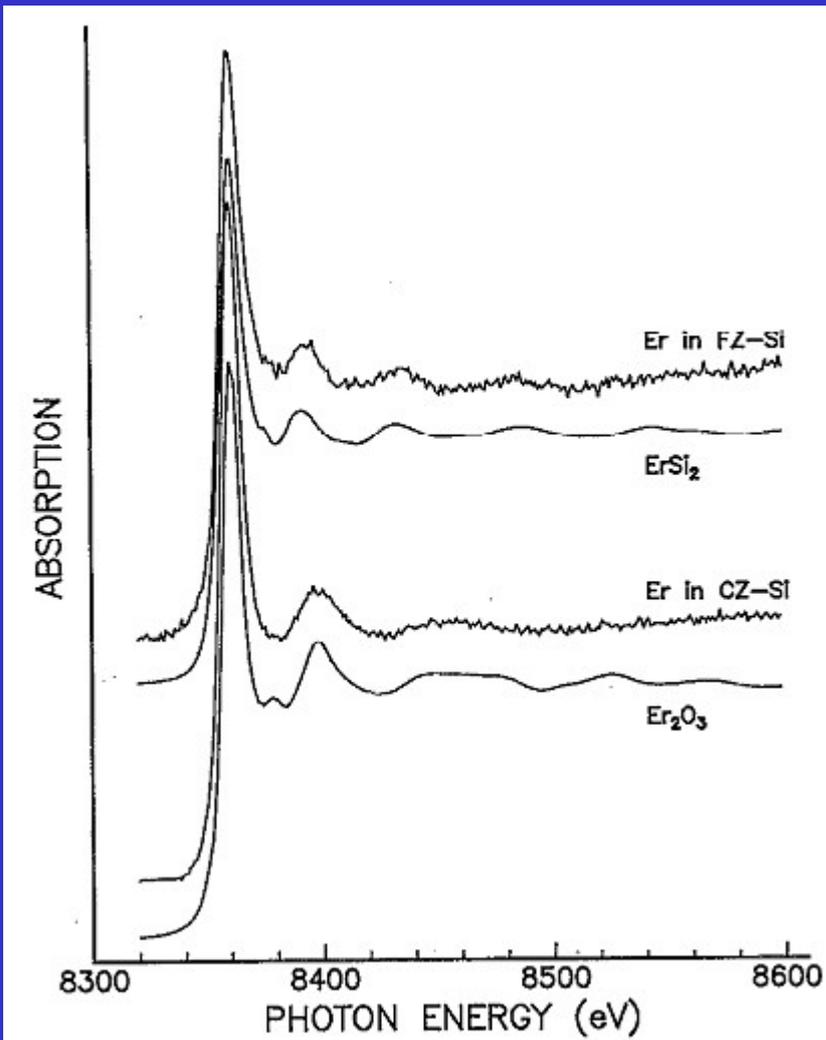
# Experimental examples

How the local information from XAS helps in explaining the luminescence properties

# Local structure of 1.54- $\mu\text{m}$ -luminescence $\text{Er}^{3+}$ implanted in Si

D. L. Adler, D. C. Jacobson, D. J. Eaglesham, M. A. Marcus, J. L. Benton, J. M. Poate, and P. H. Citrin

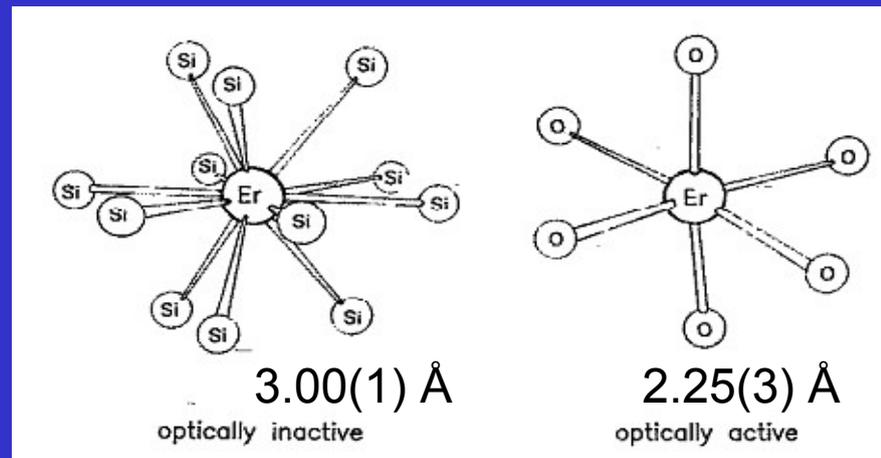
AT&T Bell Laboratories, Murray Hill, New Jersey 07974 2181 Appl. Phys. Lett. 61 (18), 2 November 1992



1<sup>st</sup> investigation on link between structure and luminescence

$10^{17}$   $\text{Er}/\text{cm}^3$  -implanted Si: FZ vs CZ substrates.

CZ-Si  $\sim 100^*$  more luminescent than FZ-Si  
CZ-Si contains  $10^{18}$   $\text{O}/\text{cm}^3$



# Evolution of the local environment around Er upon thermal annealing in Er and O co-implanted Si

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*Consiglio Nazionale delle Ricerche, Istituto Nazionale Metodologie e Tecnologie per la Microelettronica, I-95121 Catania, Italy*

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F. D'Acapito<sup>b)</sup>

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S. Mobilio

*Istituto Nazionale di Fisica Nucleare and Dipartimento di Fisica, Università di Roma III, I-00146 Rome, Italy*

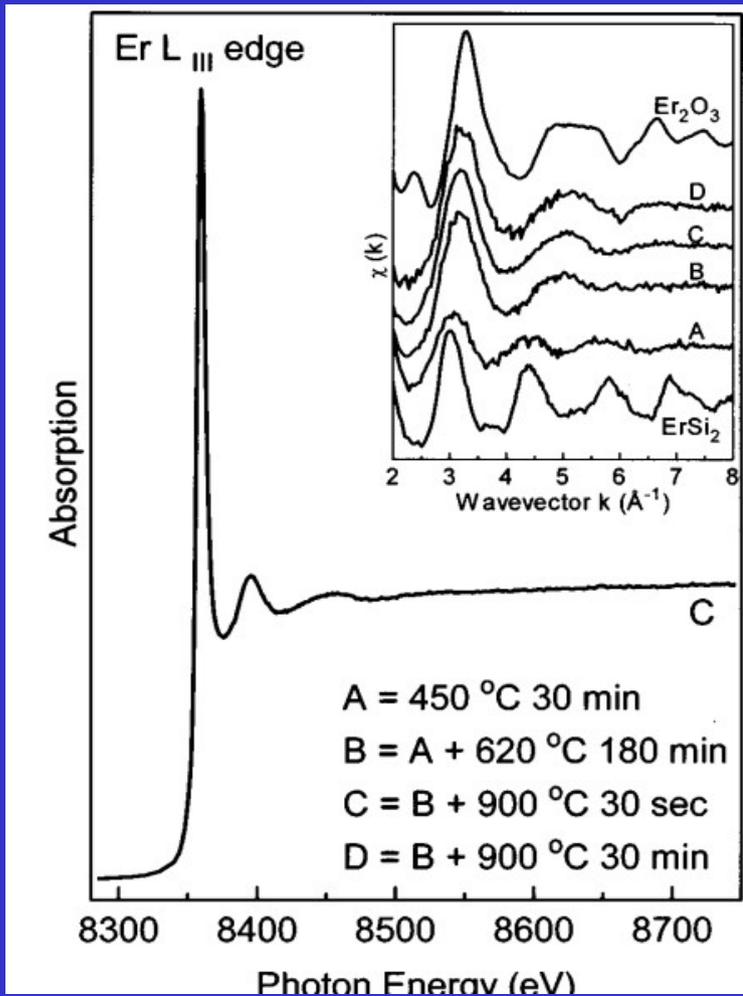
(Received 22 November 1996; accepted for publication 30 January 1997)

1712 Appl. Phys. Lett. **70** (13), 31 March 1997 0003-6951/97/70(13)/1712/3/\$10.00 © 1997 American Institute of Physics  
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Er + O implanted FZ Si (resp  $10^{19}$  and  $10^{20}$  /cm<sup>3</sup>)

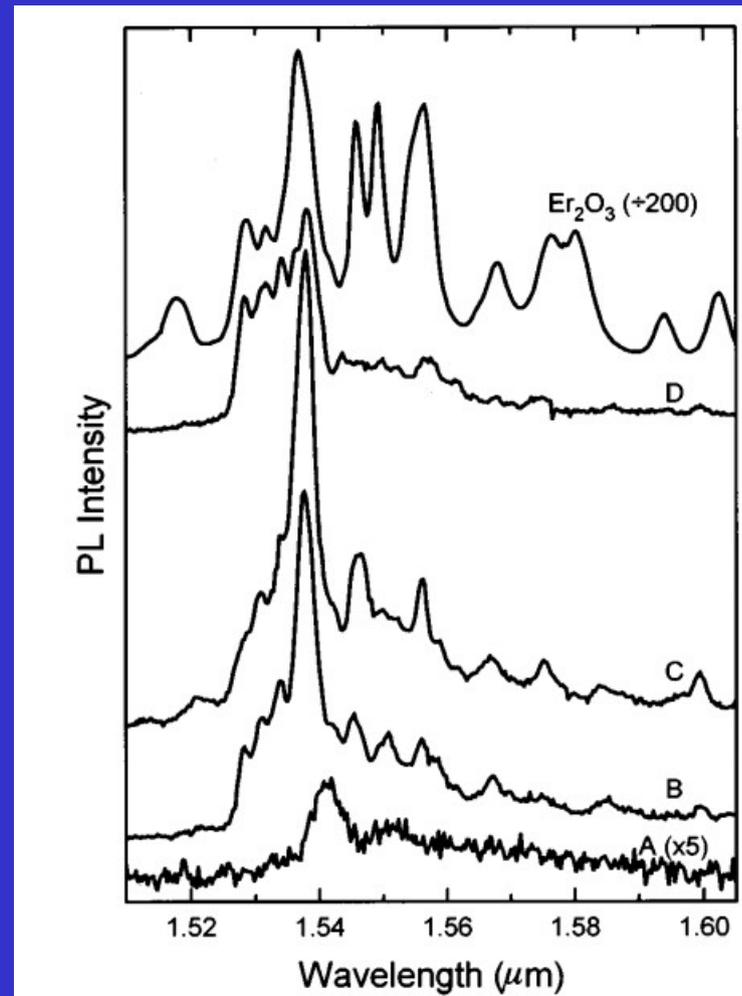
Several Annealing processes to promote re-crystallization and Er-O reaction

Comparison structure-luminescence at each stage



### Results

- A: Er-Si coordination
- B: Er-Si and Er-O
- C only Er-O
- D only Er-O more ordered



### Results

- A: barely visible PL
- B: presence of PL
- C: more intense PL
- D: less intense PL respect to C

**Environment of Erbium in  $a$ -Si:H and  $a$ -SiO<sub>x</sub>:H**

C. Piamonteze, A. C. Iñiguez, and L. R. Tessler

*Instituto de Física "Gleb Wataghin," UNICAMP, CP 6165, 13083-970, Campinas, São Paulo, Brazil*

M. C. Martins Alves and H. Tolentino

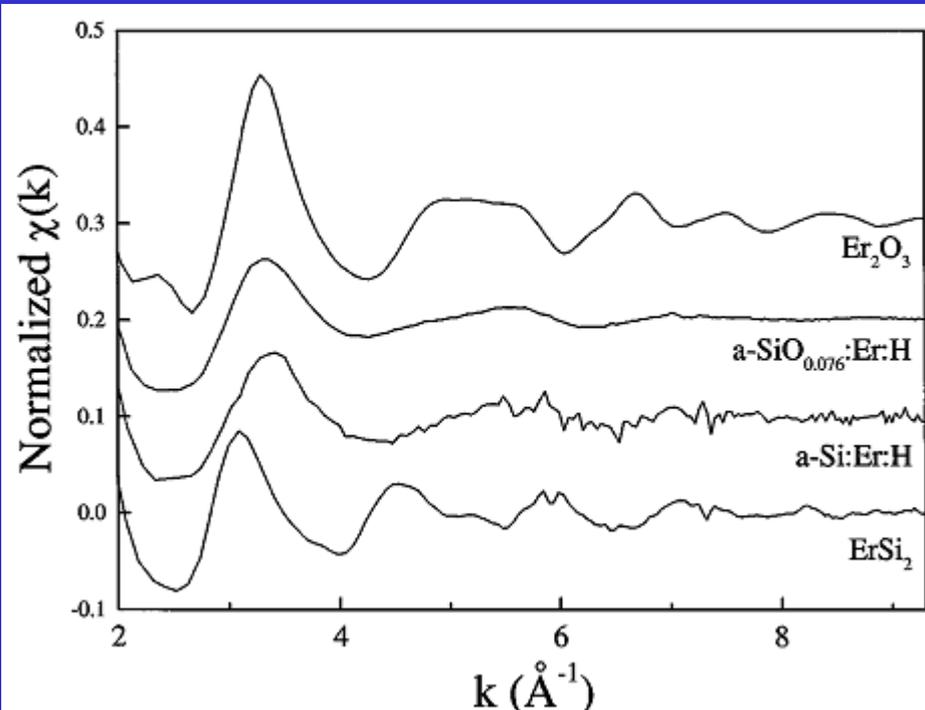
*Laboratório Nacional de Luz Síncrotron, CP 6192, 13083-970, Campinas, São Paulo, Brazil*

(Received 17 June 1998)

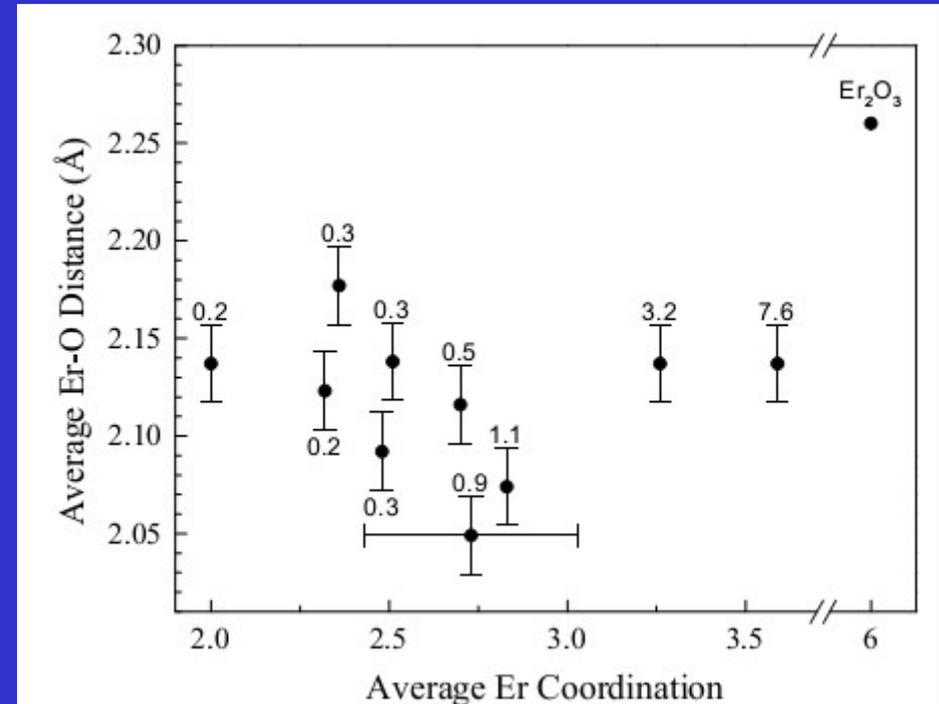
Er:aSi prepared by RF sputtering

Residual O or on purpose O doping at low level.

Creation of ErO<sub>δ</sub> complexes with a high luminescence efficiency



EXAFS spectra



N to R comparison: a lower number of neighbors corresponds to a shorter distance

The non-centrosymmetric environment favours the intra-f emission at  $1.54 \mu\text{m}$

## Er site in Er-implanted Si nanoclusters embedded in SiO<sub>2</sub>

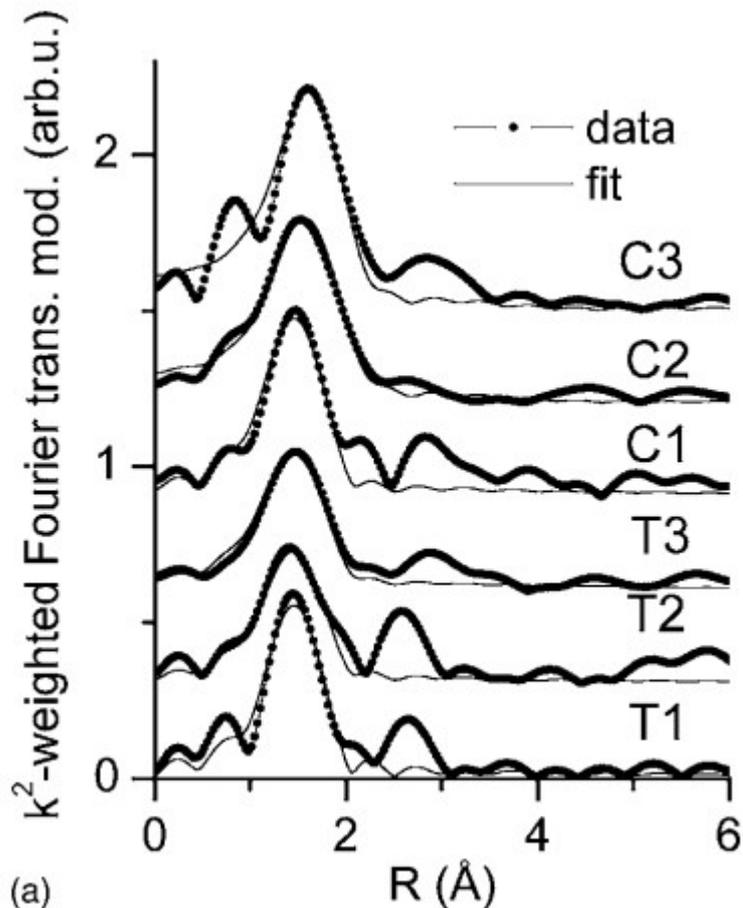
C. Maurizio,<sup>1,\*</sup> F. Iacona,<sup>2</sup> F. D'Acapito,<sup>1</sup> G. Franzò,<sup>3</sup> and F. Priolo<sup>3</sup>

<sup>1</sup>INFM-CNR, OGG-European Synchrotron Radiation Facility, GILDA-CRG, Boîte Postal 220, F-38043 Grenoble, France

<sup>2</sup>CNR-IMM, Sezione di Catania, stradale Primosole 50, I-95121 Catania, Italy

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(Received 12 July 2006; revised manuscript received 11 September 2006; published 22 November 2006)

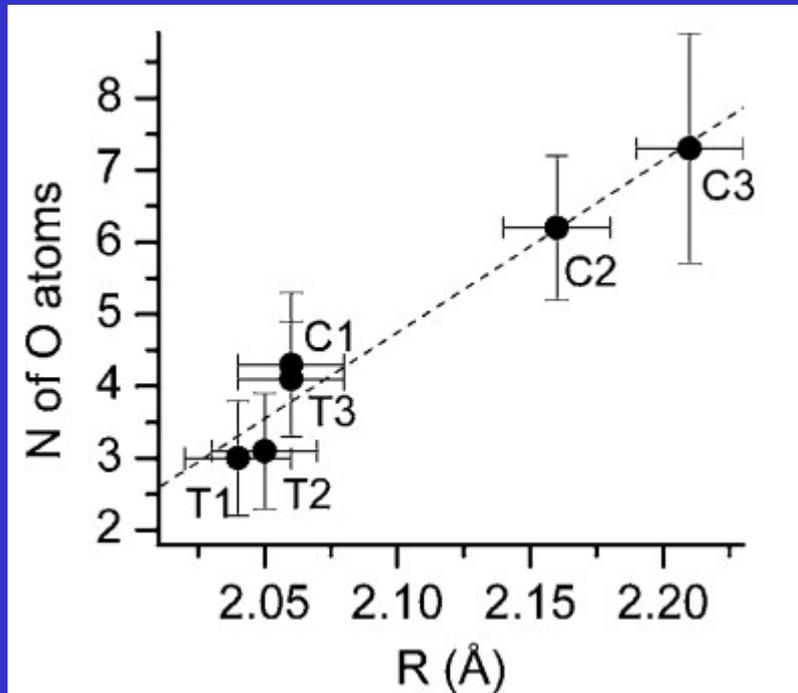


Er-implanted sub-stoichiometric Silica.  
Formation of Si nanoclusters (nc)

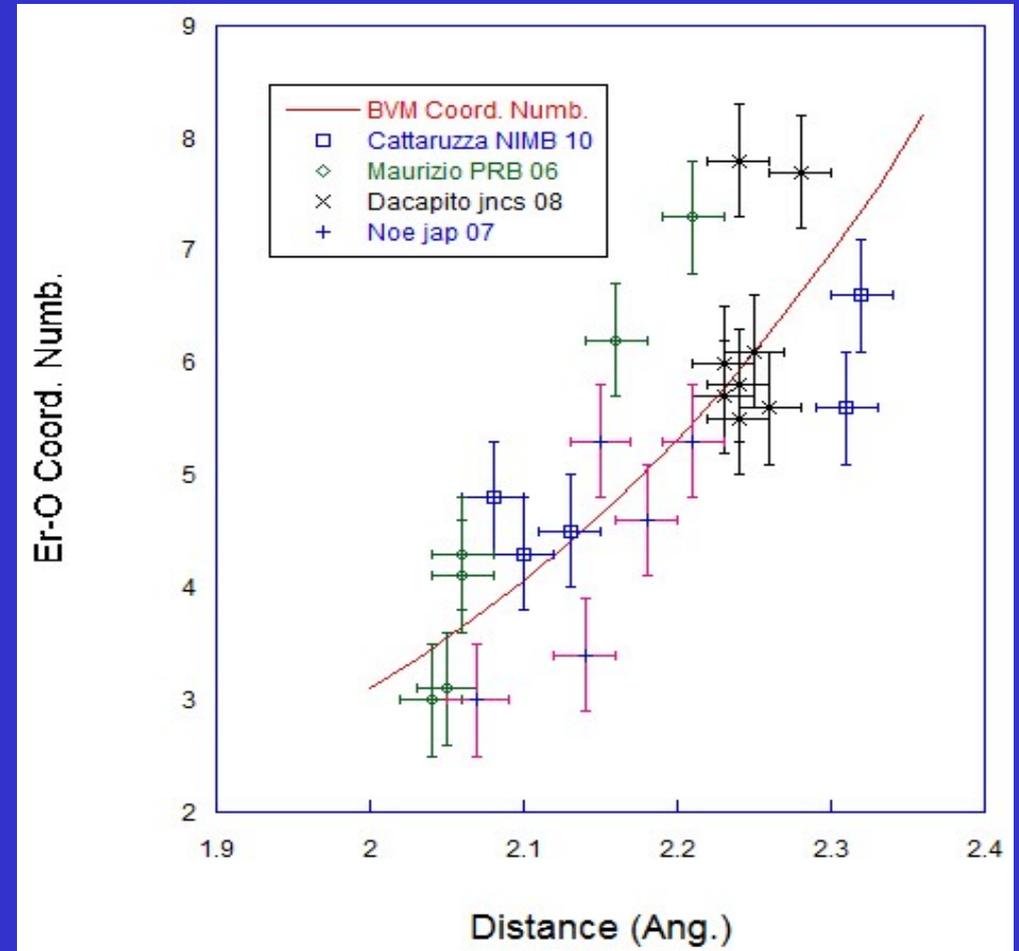
T1-T3 different Si-nc size  
C1-C2 like T3 different Er content.

sample	Preimplantation annealing temperature (°C)	Er concentration (cm <sup>-3</sup> )
T1		$5.3 \times 10^{19}$
T2	800	$5.3 \times 10^{19}$
T3	1250	$5.3 \times 10^{19}$
C1	1250	$4.5 \times 10^{19}$
C2	1250	$1.6 \times 10^{20}$
C3	1250	$1.0 \times 10^{21}$

# Neighbors vs bond length

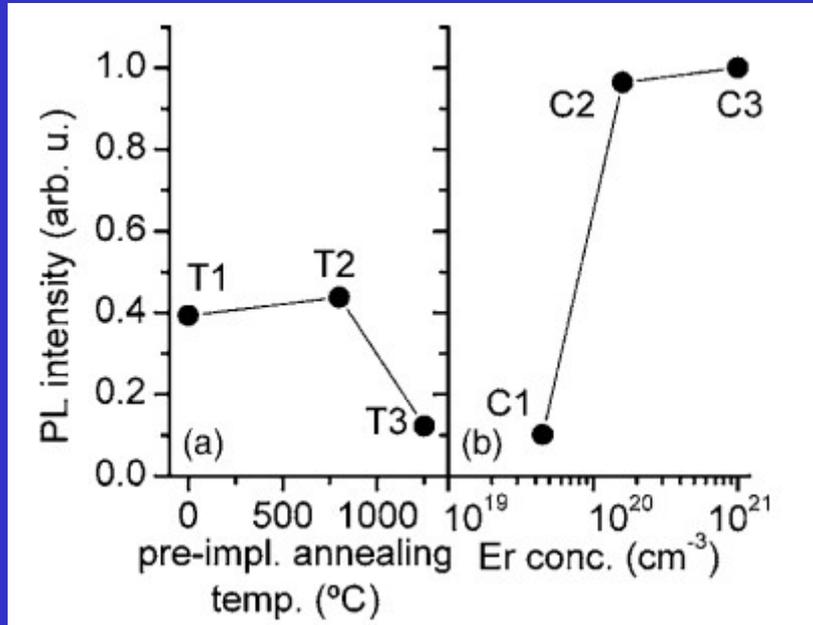


Experimental data

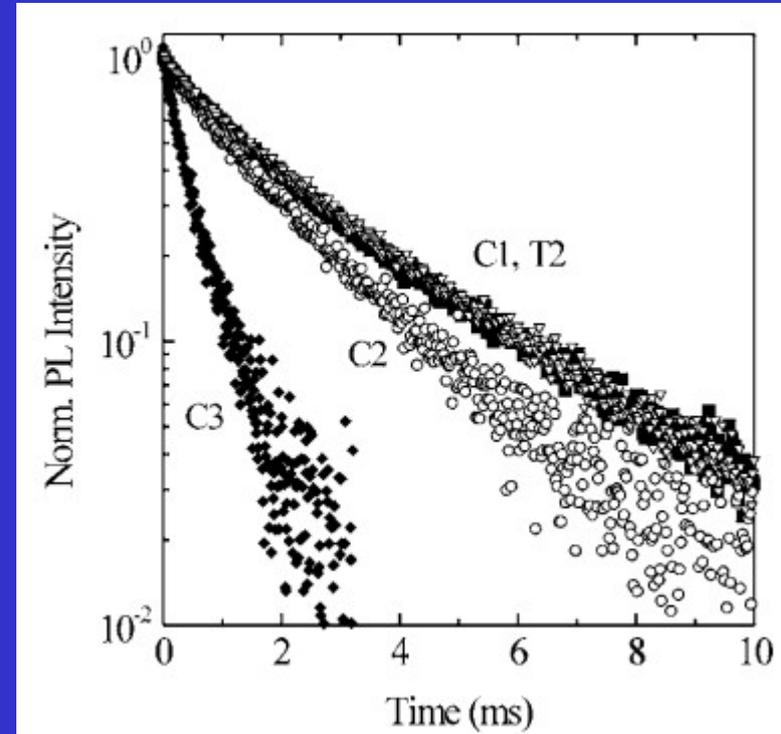


Experimental data vs prediction of Bond Valence Method

# PL properties



Intensity



Life time

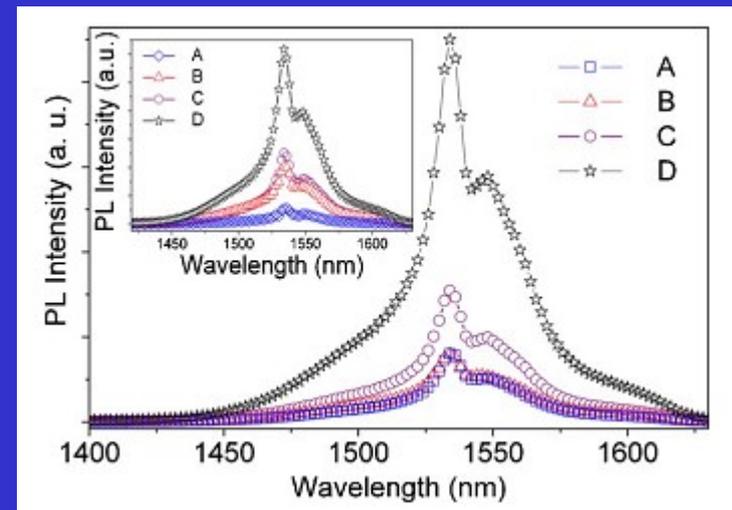
Low-O-coordinated Er plus small NC enhance the PL response

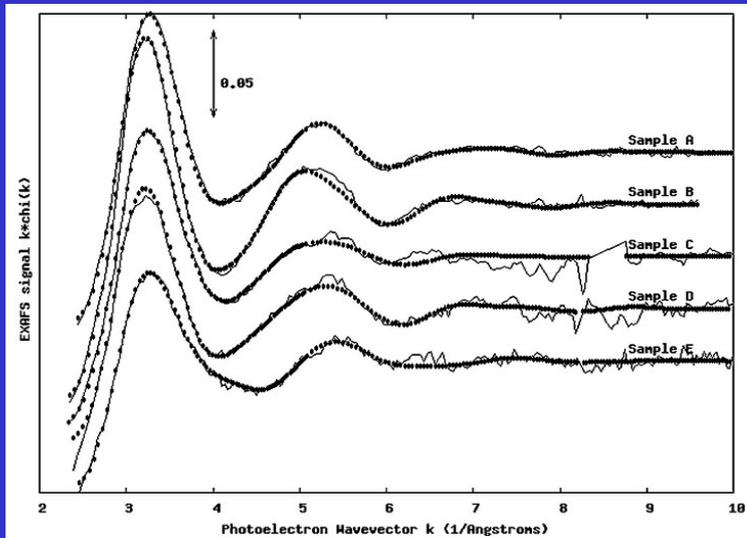
## Effect of the Er-Si interatomic distance on the Er<sup>3+</sup> luminescence in silicon-rich silicon oxide thin films

P. Noé,<sup>a)</sup> B. Salem,<sup>b)</sup> E. Delamadeleine, D. Jalabert, and V. Calvo  
*Laboratoire Silicium Nanoélectronique Photonique et Structure, DRFMC/SP2M,  
Commissariat à l'Energie Atomique, 17 rue des Martyrs, F-38054 Grenoble Cedex, France*

C. Maurizio and F. D'Acapito  
*CNR-INFM-OGG c/o ESRF, GILDA-CRG, 6, Rue Jules Horowitz, F-38043 Grenoble, France*

Er:SiO layers obtained by coevaporation  
Different atmosphere for the process: vacuum  
(A), O<sub>2</sub> (B), NH<sub>3</sub> (C, D, E).

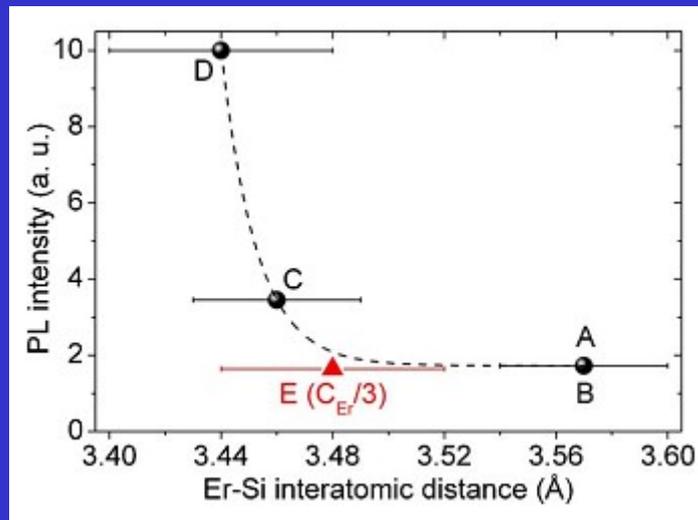




EXAFS experimental data + modelization

Sample	$N$	$R_{\text{Er-O}} (\text{\AA})$	$R_{\text{Er-Si}} (\text{\AA})$
A	4.6(2)	2.18(1)	3.57(3)
B	5.3(3)	2.21(1)	3.57(3)
C	5.3(3)	2.15(1)	3.46(3)
D	3.4(1)	2.14(2)	3.44(4)
E	3.0(2)	2.07(2)	3.48(4)

Quantitative results



Effect of the local order on the PL intensity  
Again, the lowest coordinated Er has shorter Er-O and Er-Si bonds and presents the more intense PL

# X-ray absorption fine structure determination of the local environment of $\text{Er}^{3+}$ in glass

Appl. Phys. Lett. 70 (5), 3 February 1997

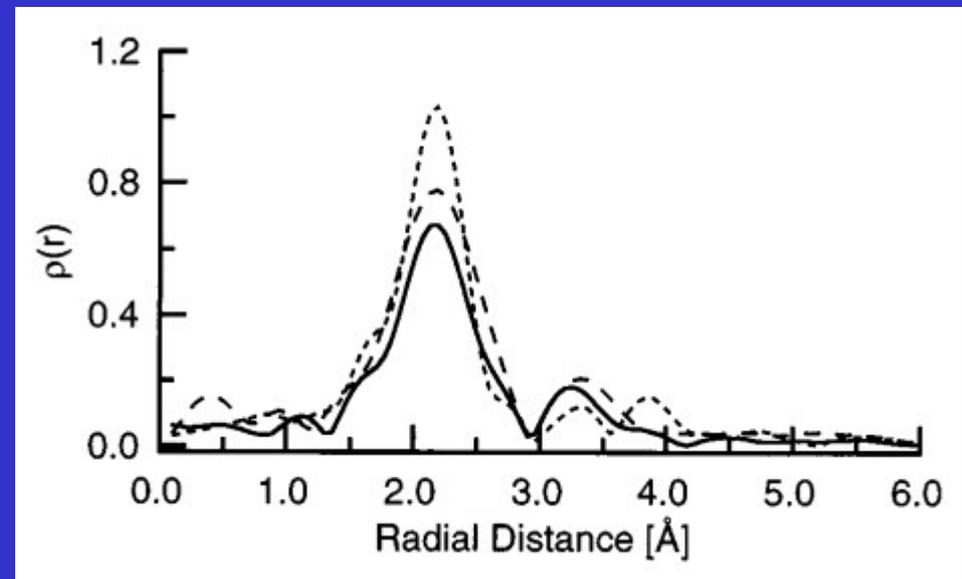
P. M. Peters<sup>a)</sup> and S. N. Houde-Walter

*The Institute of Optics, University of Rochester, Rochester, New York 14627*

Looking for the origin of concentration quenching

Various glasses: Aluminosilicate, (AS)  
Fluorosilicate (FS), Phosphate(P)

Er concentration between 0.08mole%  
and 3 mole%



FT of the highest Er glasses: AS  
(line), FS (long dashes), P (short dashes)

The second shell can be explained with Er-(Si, Al, O, P...)  
No evidence of Er-Er coordination

# Luminescent properties of local atomic order of $\text{Er}^{3+}$ and $\text{Yb}^{3+}$ ions in aluminophosphate glasses

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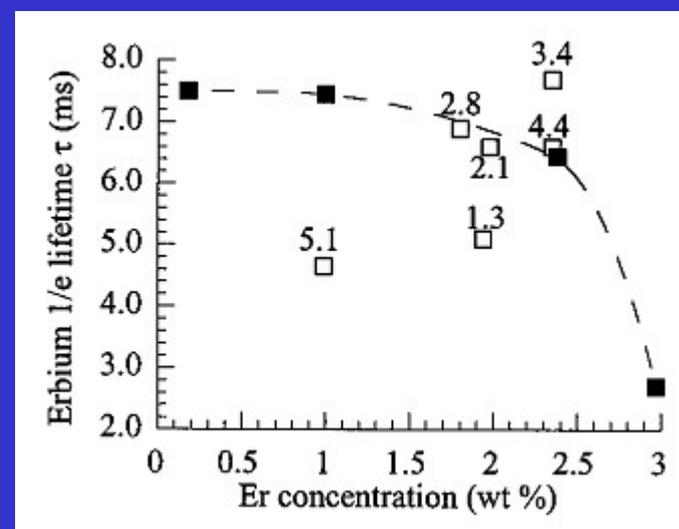
P. Bruno, D. Barbier, and J. Philipsen

*Teemphotronics 13, Chemin du Vieux Chêne, F-38240 Meylan, France*

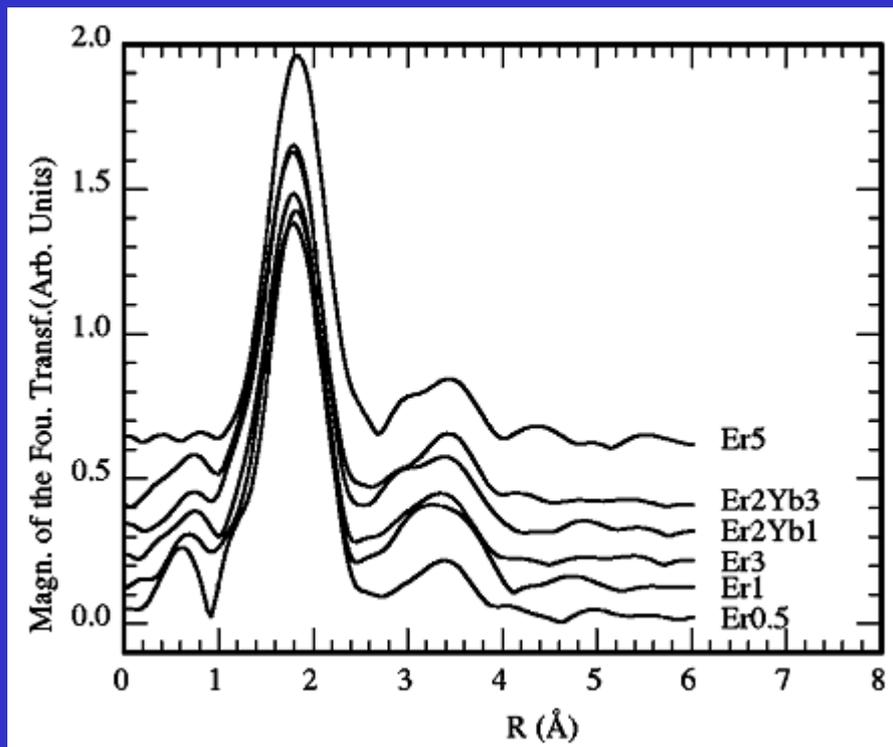
Looking for the origin of concentration quenching

Er Phosphate glasses obtained by melt

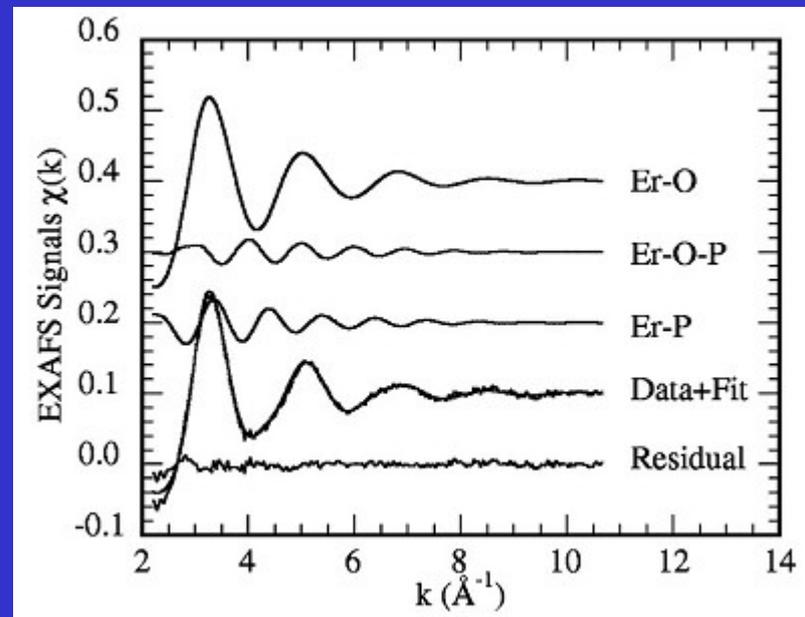
Is concentration quenching due to a direct Er-Er bond ?



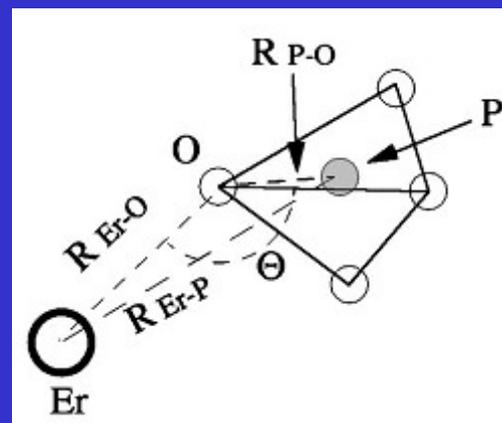
PL lifetime as a function of the Er concentration



Fourier Transforms of the EXAFS data. A second shell is clearly visible but it is present on all the samples



Data fitting with the proposed structural model



The second shell is due to Er-P coordination bridged by an O. Er-O-P angle well defined

**Structure of Er-O complexes in crystalline Si**

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A. Terrasi, G. Franzó, and F. Priolo

*INFN and Dipartimento di Fisica, Università di Catania, Corso Italia 57, I-95129 Catania, Italy*

Sample	$N_{Er-O}$ $\pm 0.6$	$R_{Er-O}$ $\pm 0.02 \text{ \AA}$	$\Theta_{Er-O-Si}$ $\pm 4 \text{ deg}$	$R_{Er-Si}$ $\pm 0.03 \text{ \AA}$
33	5.7	2.22	134	3.55
33C	5.6	2.22	137	3.59
33D	5.7	2.23	135	3.62
33E	5.5	2.23	137	3.60
49	5.0	2.23	135	3.58
49C	5.8	2.22	136	3.58
49D	5.8	2.23	137	3.59
49E	4.8	2.24	136	3.59
145AD	5.5	2.23	138	3.62
92AB	5.9	2.25	136	3.63

**Local order around Er<sup>3+</sup> ions in SiO<sub>2</sub>–TiO<sub>2</sub>–Al<sub>2</sub>O<sub>3</sub> glassy films studied by EXAFS**

F. d'Acapito <sup>a,\*</sup>, S. Mobilio <sup>b</sup>, P. Gastaldo <sup>c</sup>, D. Barbier <sup>d</sup>, Luís F. Santos <sup>e</sup>, Orlando Martins <sup>e</sup>, Rui M. Almeida <sup>e</sup>

Sample	$N_{Er-O}$ $\pm 0.6$	$R_{Er-O} \pm 6$ $\times 10^{-4}$ (nm)	$\Theta_{Er-O-SNN}$ $\pm 3$ (deg)	$R_{Er-SNN} \pm 1$ $\times 10^{-3}$ (nm)
0A0.2	6.8	0.2269	140	0.359
0A0.5	6.7	0.2271	141	0.363
9A0.2	6.4	0.2245	135	0.361
9A0.5	6.6	0.2265	135	0.365
9A1.0	6.2	0.2257	136	0.364
9A1.75	6.1	0.2256	138	0.362
0A0.25	6.7	0.2275	142	0.360
2A0.25	6.7	0.2277	140	0.361
5A0.25	6.6	0.2266	138	0.362
7A0.25	6.7	0.2265	137	0.365
9A0.25	6.5	0.2260	137	0.363
11A0.25	6.6	0.2258	136	0.365
17A0.25	6.6	0.2251	133	0.365

Er-O-NN angle well defined, about  $138 \pm 4 \text{ deg}$

## Local environment of rare-earth dopants in silica–titania–alumina glasses: An extended x-ray absorption fine structure study at the *K* edges of Er and Yb

F. d'Acapito<sup>a)</sup>

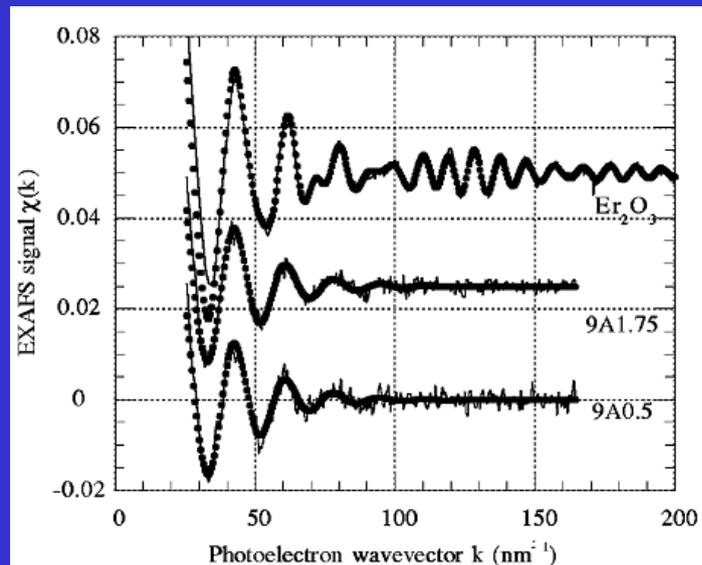
*Istituto Nazionale per la Fisica della Materia—OGG, 6 Rue Jules Horowitz, F-38043 Grenoble, France*

S. Mobilio

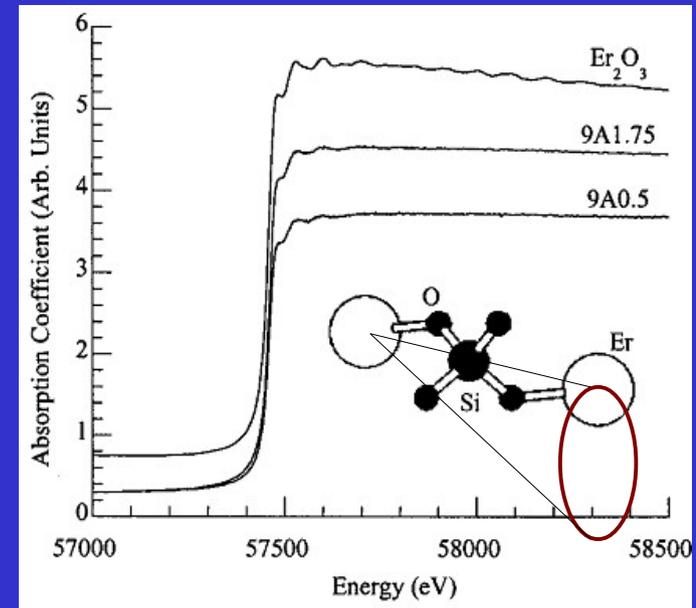
*Università "Roma Tre," Via della Vasca Navale, I-00184 Roma, Italy*

L. Santos and Rui M. Almeida

*Departamento de Engenharia de Materiais/INESC, Instituto Superior Técnico, Av. Rovisco Pais, 1049-001 Lisboa, Portugal*

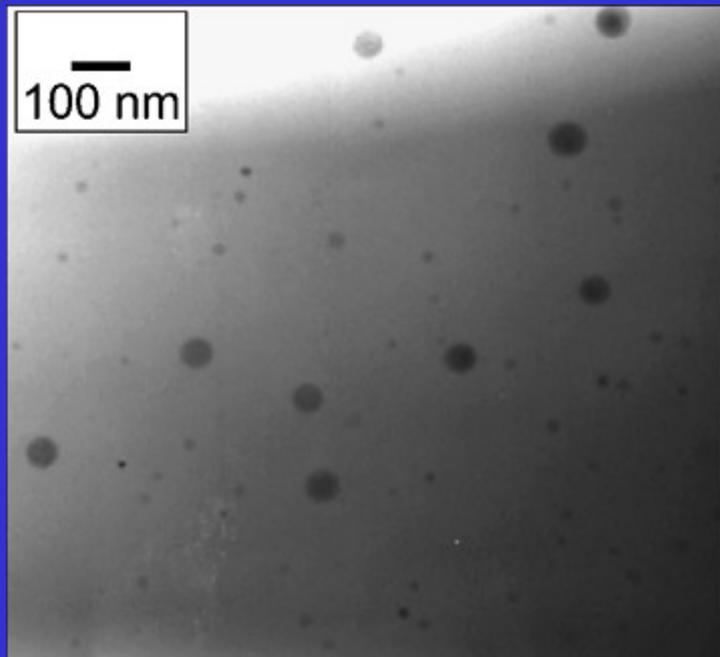


EXAFS data



Proposed model for Er clustering:  
two ions bound to the same SiO<sub>4</sub>  
tetrahedron

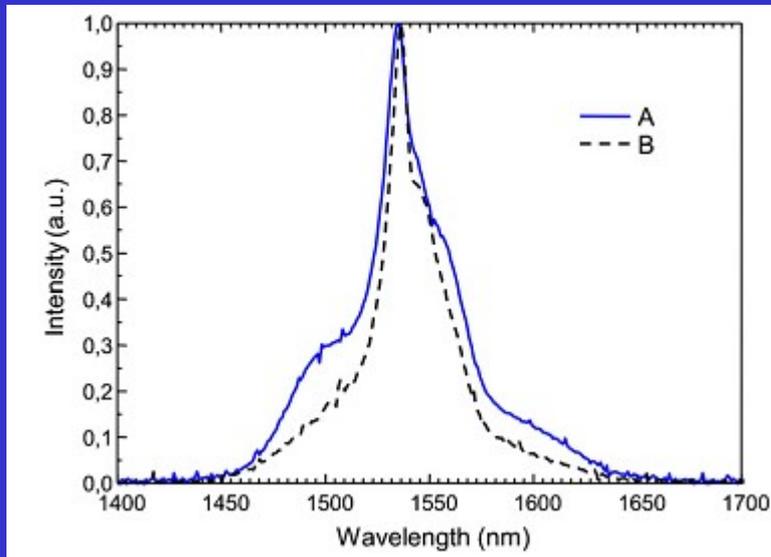
Investigation on fibre preforms (diam. ~500 μm)  
Glass: SiO<sub>2</sub>–GeO<sub>2</sub>–P<sub>2</sub>O<sub>5</sub>–Er<sub>2</sub>O<sub>3</sub> with (A) and without (B) CaO



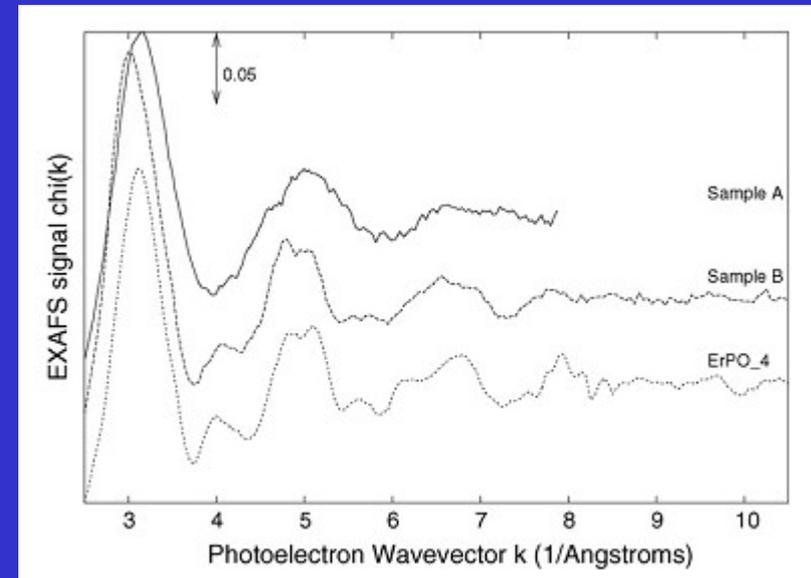
TEM of an A sample

- The addition of Ca promotes the formation of nanoparticles
- NP rich in Ca, P, Er
- NP amorphous

# PL and local structure



PL of A and B samples: the former is broader and less structured



EXAFS

A: glassy like spectrum (only a single frequency)

B: modulated spectrum identical to ErPO<sub>4</sub>.

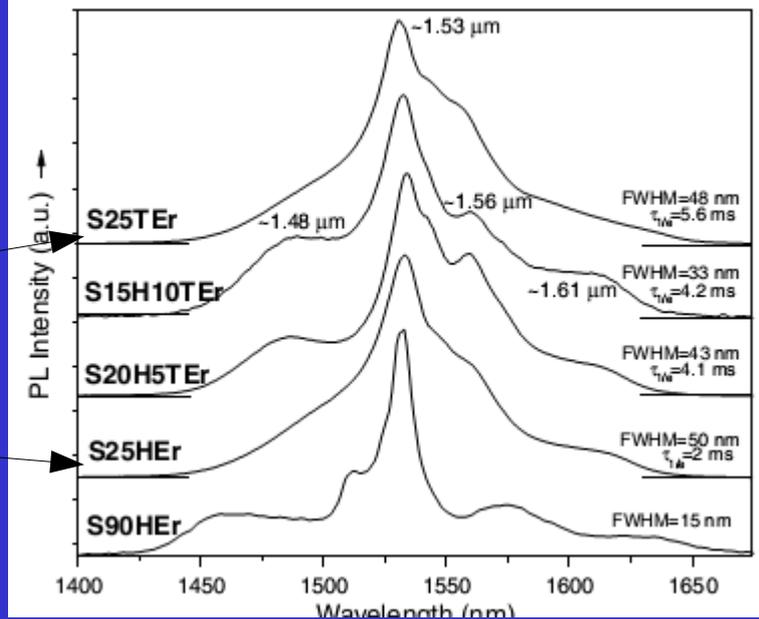
Conclusion

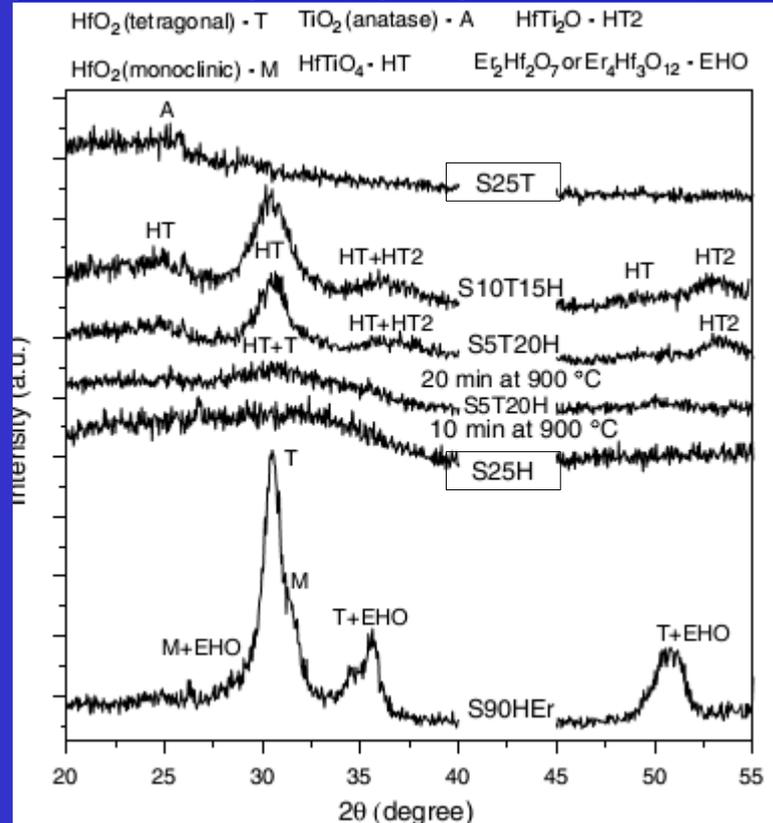
Er has a strong affinity with P to form ErPO<sub>4</sub> and the addition of Ca helps in dispersing Er

EXAFS study of the  $\text{Er}^{3+}$  ion coordination in  $\text{SiO}_2\text{-TiO}_2\text{-HfO}_2$  sol-gel filmsFrancesco d'Acapito <sup>a,\*</sup>, Ana C. Marques <sup>b</sup>, Luís F. Santos <sup>b</sup>, Rui M. Almeida <sup>b</sup><sup>a</sup> CNR-INFM-OGG, c/o ESRF GILDA CRG BP220, 6 Rue Jules Horowitz, F-38043 Grenoble, France<sup>b</sup> Departamento de Engenharia de Materiais/ICEMS, Instituto Superior Técnico/TULisbon, Av. Rovisco Pais, 1049-001 Lisboa, PortugalSilica-Titania-Hafnia layers produced by sol-gel  
Several annealing treatments

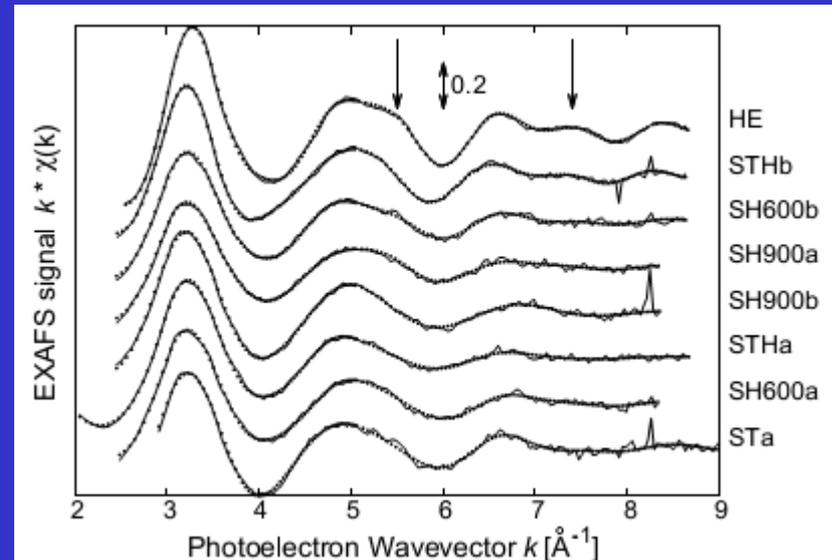
Acronym	Composition (molar ratio)	Densification heat-treatment	Post-implantation heat-treatment
STa	75 $\text{SiO}_2$ -25 $\text{TiO}_2$	5 min @ 600 °C	10 min @ 600 °C
STHa	75 $\text{SiO}_2$ -10 $\text{TiO}_2$ -15 $\text{HfO}_2$	5 min @ 600 °C	10 min @ 600 °C
STHb	75 $\text{SiO}_2$ -10 $\text{TiO}_2$ -15 $\text{HfO}_2$	5 min @ 600 °C	5 min @ 900 °C
SH600a	75 $\text{SiO}_2$ -25 $\text{HfO}_2$	5 min @ 600 °C	10 min @ 600 °C
SH600b	75 $\text{SiO}_2$ -25 $\text{HfO}_2$	5 min @ 600 °C	5 min @ 900 °C
SH900a	75 $\text{SiO}_2$ -25 $\text{HfO}_2$	5 min @ 900 °C	10 min @ 600 °C
SH900b	75 $\text{SiO}_2$ -25 $\text{HfO}_2$	5 min @ 900 °C	5 min @ 900 °C

R.M. Almeida, A.C. Marques / Journal of Non-Crystalline Solids 352 (2006) 475–482





XRD from samples



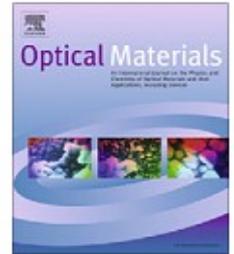
No evidence of crystallization  
 PL remains broad  
 Evidence of Er-Hf  
 coordination upon annealing



Contents lists available at SciVerse ScienceDirect

# Optical Materials

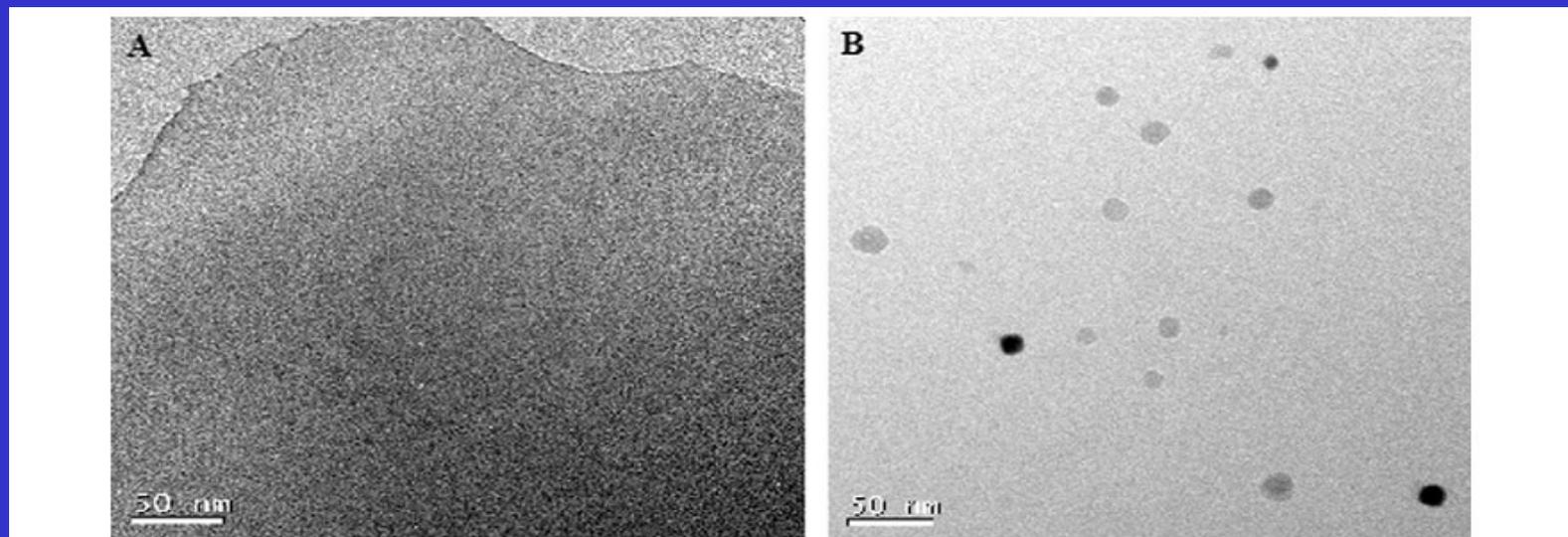
journal homepage: [www.elsevier.com/locate/optmat](http://www.elsevier.com/locate/optmat)



## Incorporation of $\text{Yb}^{3+}$ ions in multicomponent phase-separated fibre glass preforms

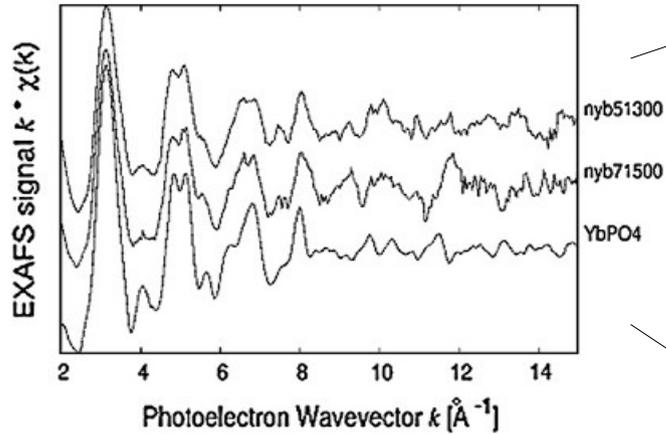
C.I. Oppo<sup>a</sup>, R. Corpino<sup>a</sup>, P.C. Ricci<sup>a</sup>, M.C. Paul<sup>b</sup>, S. Das<sup>b</sup>, M. Pal<sup>b</sup>, S.K. Bhadra<sup>b</sup>, S. Yoo<sup>c</sup>, M.P. Kalita<sup>c</sup>, A.J. Boyland<sup>c</sup>, J.K. Sahu<sup>c</sup>, P. Ghigna<sup>d</sup>, F. d'Acapito<sup>e,\*</sup>

Phase separated fibers: a way to insert Yb in crystalline environment  
Yb-doped Ytria-Alumina-Silica with P2O5. Target: obtain Yb-doped Y2O3.

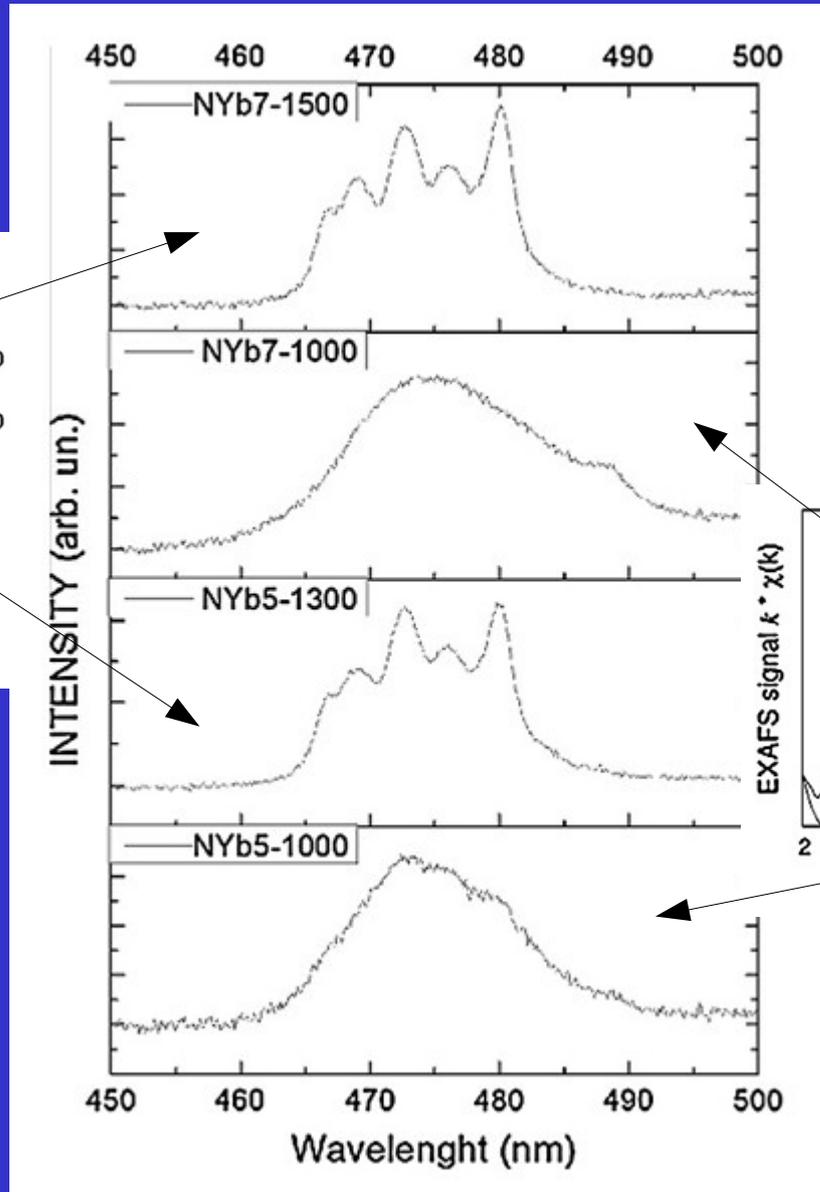


**Fig. 1.** TEM pictures two annealed preform samples (A) NYb5-1000 annealed at 1000 °C and (B) NYb5-1300 annealed at 1300 °C.

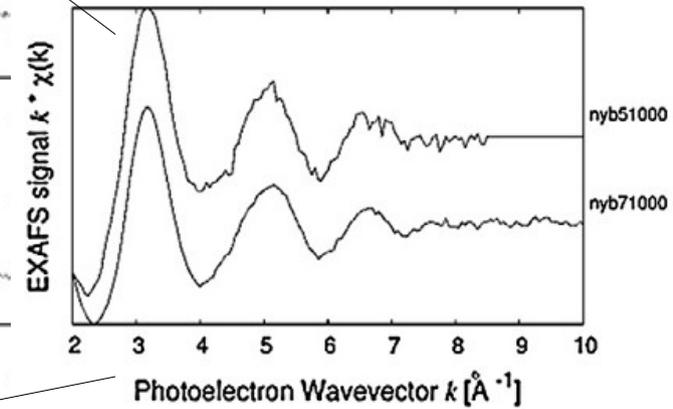
# Structure & PL



EXAFS high temp samples



Anti-stokes PL,  $\lambda_{\text{exct}} = 978 \text{ nm}$



EXAFS low temp samples

# Conclusion

XAS is a tool for accessing the local structure of dopants in glassy matrices.

REs in glasses: clear link between structure and optical properties.